

Form PTO-7449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. JM34006DIV		SERIAL NO. 10/027,992	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Janine K. Kardokus et al.			
					FILING DATE December 19, 2001		GROUP 1742	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
SE	AA	6,440,243 B1	08-2002	Tan et al.				
	AB	6,277,254 B1	08-2001	Tan et al.				
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	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
SE	AM	11323539	11-1999	Japan			✓	
	AN	0441408A2	08-1991	EPO			✓	
	AO	EP1026284A1	09-2000	EPO			✓	
	AP	JP2000239836A	09-2000	Japan			✓	
AQ								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
A	AR	Yeon et al., "Electrical Characteristics of the MOD-derived SrBi ₂ xTa ₂ O ₉ and SrBi ₂ .4(TA,Nb) ₂ O ₉ Thin Films", Journal of Materials Science, 35(10), pgs. 2405-2411, May 15, 2000. Abstract only.						
Z	AS	Yan et al., "Preparation on the [(Pb,Lu) (Zr,Ti)O ₃] Ferroelectric Thin Films by Using the Sol-Gel Processing", Piezoelectrics and Acoustooptics, Volume 17, issue n 5, October 1995, pgs. 24-27.						
	AT							
EXAMINER S. Kastler				DATE CONSIDERED 2-04				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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